

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12406-060US1	Application No. 09/989,362
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Auch et al.	
		Filing Date November 20, 2001	Group Art Unit 2815

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
Jbe	AA	2004/0217703	11/04/2004	Wittmann et al.			
	AB	4,253,741	03/03/1981	Nakauchi et al.			
	AC	4,842,946	06/27/1989	Foust et al.			
	AD	5,041,395	08/20/1991	Steffen			
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	AY	6,888,237	05/03/2005	Guenther			

Examiner Signature <i>Jasmine Clark</i>	Date Considered <i>9/20/7</i>
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
<i>Ybc</i>	AZ	WO 00/69002 A1	11/16/2000	WIPO				
<i>Ybc</i>	AAA	WO 01/44866 A1	06/21/2001	WIPO				

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
<i>Ybc</i>	ABB	Cheang, P. et al. "An Optimized Process for Ultrathick Photosensitive Polyimide Applications", SEMICON Taiwan 1996, pp. 1-12.
	ACC	
	ADD	
	AEE	

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